

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claims 1-20 (canceled)

Claim 21 (previously presented): A method comprising:

wirelessly receiving a single test command on a plurality of wireless devices formed on a wafer via radio frequency circuitry of each of the plurality of wireless devices operable in a test mode and normal operation; and

simultaneously testing the plurality of wireless devices in response to receiving the single test command.

Claim 22 (previously presented): The method of claim 21, further comprising switching all of the plurality of wireless devices on to wirelessly receive the single test command.

Claim 23 (previously presented): The method of claim 22, further comprising switching on a transistor coupled to each of the plurality of wireless devices to switch all of the plurality of wireless devices on.

Claim 24 (previously presented): The method of claim 21, further comprising wirelessly receiving the single test command without an antenna coupled to the plurality of wireless devices.

Claim 25 (previously presented): The method of claim 24, further comprising wirelessly receiving the single test command via one or more pads formed on each of the plurality of wireless devices.

Claim 26 (previously presented): The method of claim 24, further comprising wirelessly receiving the single test command via a power line formed on each of the plurality of wireless devices.

Claim 27 (previously presented): The method of claim 21, further comprising communicating with individual ones of the plurality of wireless devices regarding test results.

Claim 28 (previously presented): The method of claim 27, further comprising communicating with the individual ones of the plurality of wireless devices based on a unique identifier.

Claim 29 (previously presented): The method of claim 21, further comprising eliminating any of the plurality of the wireless devices that does not identify itself in response to the single test command.

Claim 30 (previously presented): The method of claim 29, further comprising next eliminating any of the plurality of wireless devices that fail a volatile memory test.

Claim 31 (previously presented): The method of claim 30, further comprising next eliminating any of the plurality of wireless devices that fail a digital circuitry test.

Claim 32 (previously presented): The method of claim 31, further comprising next eliminating any of the plurality of wireless devices that fail a mixed signal interface test.

Claim 33 (previously presented): A system comprising:

a test unit to issue a single test command for transmission to a plurality of wireless devices formed on a wafer, the single test command to cause testing of the plurality of wireless devices via radio frequency circuitry of each of the plurality of wireless devices operable in a test mode and normal operation of the wireless device in parallel; and

an antenna coupled to the test unit to wirelessly transmit the single test command for receipt by the plurality of wireless devices.

Claim 34 (previously presented): The system of claim 33, further comprising a wafer sorter coupled to the test unit.

Claim 35 (previously presented): The system of claim 33, wherein the test unit is configured to selectively address selected ones of the plurality of wireless devices to receive test results therefrom.

Claim 36 (previously presented): The system of claim 35, wherein the system is configured to provide power in parallel to the plurality of wireless devices via a single power pad on the wafer.

Claim 37 (currently amended): An apparatus comprising:

a wafer having a plurality of wireless devices formed thereon, wherein each of the plurality of wireless devices comprises an analog portion including a cellular radio core and a short-range wireless transceiver core coupled to the cellular radio core, and a digital portion including a processor coupled to the cellular radio core and the short-range wireless transceiver core to handle a plurality of wireless communication protocols and a memory coupled to the processor, the wafer comprising:

a power pad coupled to each of the plurality of wireless devices to provide a power supply voltage thereto during a test operation; and

a ground pad coupled to each of the plurality of wireless devices to provide a reference voltage thereto during the test operation.

Claim 38 (previously presented): The apparatus of claim 37, further comprising a plurality of transistors, each coupled to provide the power supply voltage to a corresponding one of the plurality of wireless devices under control of a voltage on a bit pad.

Claim 39 (previously presented): The apparatus of claim 37, wherein each of the wireless devices is configured to directly receive a test command from a tester wirelessly.

Claims 40 – 41 (cancel)

Claim 42 (currently amended): The apparatus of claim [[41]] 37, wherein the short-range wireless transceiver core is configured to wirelessly receive signals from a tester without a dedicated antenna.